

WHAT IS CLAIMED IS

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1. A magnetic head, comprising:  
a magneto-resistive film having a  
ferromagnetic free layer at a top part thereof, said  
ferromagnetic free layer changing a magnetization  
10 thereof in response to an external magnetic field;  
first and second magnetic domain control  
patterns provided on said ferromagnetic free layer,  
each of said first and second magnetic domain control  
patterns causing a pinning of magnetization in said  
15 ferromagnetic free layer in the vicinity thereof;  
a first electrode provided on said  
ferromagnetic free layer in contact therewith at a  
region located between said first and second magnetic  
domain control patterns; and  
20 a second electrode provided in electrical  
contact with a bottom surface of said magneto-  
resistive film.

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2. A magnetic head as claimed in claim 1,  
further comprising a first insulating film covering  
said first magnetic domain control pattern and a  
30 second insulating film covering said second magnetic  
domain control pattern, such that said first  
insulating film is interposed between said first  
magnetic domain control pattern and said first  
electrode and such that said second insulating film is  
35 interposed between said second magnetic domain control  
pattern and said first electrode.

3. A magnetic head as claimed in claim 2,  
wherein said first and second insulating films have a  
generally identical thickness.

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4. A magnetic head, comprising:

a magneto-resistive film;

10 a pair of magnetic domain control patterns  
provided at both lateral sides of said magneto-  
resistive film, each of said magnetic domain control  
patterns causing a pinning of magnetization in said  
magneto-resistive film in the vicinity thereof;

15 a pair of electrodes provided respectively  
on said pair of magnetic domain control regions with a  
mutual separation from each other, each electrode  
having a tip-end part extending over said magneto-  
resistive film toward the other electrode,

20 wherein each tip-end part extends beyond  
said domain control region, on which said electrode  
having said tip-end part is provided, with a  
protruding distance of 0.25  $\mu$ m or less.

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5. A magnetic disk apparatus, comprising:

a rotary magnetic disk; and

30 a magnetic head scanning over a surface of  
said magnetic disk,

said magnetic head comprising:

a magneto-resistive film having a  
ferromagnetic free layer at a top part thereof, said  
35 ferromagnetic free layer changing a magnetization  
thereof in response to an external magnetic field;  
first and second magnetic domain control

patterns provided on said ferromagnetic free layer,  
each of said first and second magnetic domain control  
patterns causing a pinning of magnetization in said  
ferromagnetic free layer in the vicinity thereof;

5           a first electrode provided on said  
ferromagnetic free layer in contact therewith at a  
region located between said first and second magnetic  
domain control patterns; and

10           a second electrode provided in electrical  
contact with a bottom surface of said magneto-  
resistive film.

15           6. A magnetic disk apparatus, comprising:  
a rotary magnetic disk; and  
a magnetic head scanning over a surface of  
said magnetic disk,

20           said magnetic head comprising:  
a magneto-resistive film;  
a pair of magnetic domain control patterns  
provided at both lateral sides of said magneto-  
resistive film, each of said magnetic domain control  
25   patterns causing a pinning of magnetization in said  
magneto-resistive film in the vicinity thereof;

          a pair of electrodes provided respectively  
on said pair of magnetic domain control regions with a  
mutual separation from each other, each electrode  
30   having a tip-end part extending over said magneto-  
resistive film toward the other electrode,

          wherein each tip-end part extends beyond  
said domain control region, on which said electrode  
having said tip-end part is provided, with a  
35   protruding distance of 0.25  $\mu\text{m}$  or less.

7. A method of fabricating a magnetic head, comprising the steps of:

forming a magneto-resistive film;

forming a resist film on said magneto-  
5 resistive film;

patterning said resist film to form a resist pattern;

conducting a first process while using the resist pattern as a mask;

10 causing a shrinkage in said resist pattern;  
and

conducting a second process while using the shrunken resist pattern as a mask.

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8. A method of fabricating a magnetic head, comprising the steps of:

20 forming a magneto-resistive film on a substrate such that said magneto-resistive film includes a ferromagnetic layer on a top part thereof;

depositing a resist film on said magneto-resistive film such that said resist film covers said  
25 ferromagnetic layer;

patterning said resist film to form a resist pattern;

depositing a high-coercive magnetic film having a coercive force larger than a coercive force  
30 of said ferromagnetic layer in said magneto-resistive film on said magneto-resistive film while using said resist pattern as a mask, to form a pair of high-coercive magnetic regions at both lateral sides of said resist pattern;

35 causing a shrinkage in said resist pattern to form a shrunken resist pattern;

depositing an insulating film on said

magneto-resistive film such that said insulating film covers said high-coercive magnetic regions and further said shrunken resist pattern;

removing said shrunken resist pattern

5 together with a part of said insulating film covering said shrunken resist pattern so as to expose a part of said magneto-resistive film on which said shrunken resist pattern has been provided; and

10 depositing an electrode layer on said insulating film such that said electrode layer makes a contact with said exposed part of said magneto-resistive film.

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9. A method of fabricating a magnetic head, comprising the steps of:

20 forming a magneto-resistive film on a substrate;

forming a resist film on said magneto-resistive film;

patterning said resist film to form a resist pattern;

25 patterning said magneto-resistive film while using said resist pattern as a mask to form a magneto-resistive pattern;

30 depositing a magnetic film having a coercive force larger than a coercive force of said magneto-resistive film while using said resist pattern as a mask, such that a pair of high-coercive magnetic regions having a large coercive force are formed at both lateral sides of said magneto-resistive pattern from said ferromagnetic film;

35 causing a shrinkage in said resist pattern; depositing a conductive layer on said magneto-resistive film while using said shrunken

